

# N-Channel 150 V (D-S) MOSFET

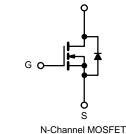
PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}(\Omega)$	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)		
150	0.074 at V <sub>GS</sub> = 10 V	25.4	23 nC		
150	0.077 at V <sub>GS</sub> = 8 V	22.5	23110		

#### **FEATURES**

- Halogen-free According to IEC 61249-2-21 Definition
- Extremely Low Q<sub>gd</sub> for Switching Losses
- 100 % R<sub>g</sub> Tested
- 100 % Avalanche Tested
- Compliant to RoHS Directive 2002/95/EC







#### **APPLICATIONS**

· Primary Side Switch

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage		$V_{DS}$	150	V	
Gate-Source Voltage		$V_{GS}$	± 20	V	
	T <sub>C</sub> = 25 °C		25.4		
Continuous Drain Current /T 150 °C)	T <sub>C</sub> = 70 °C	1 . [	23.1		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	l lo	15.5 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C	1   [	14.5 <sup>b, c</sup>	Α	
Pulsed Drain Current		I <sub>DM</sub>	50		
Continuous Source-Drain Diode Current	T <sub>C</sub> = 25 °C		4.5		
Continuous Source-Diain Diode Current	T <sub>A</sub> = 25 °C	Is	2.6 <sup>b, c</sup>		
Single Pulse Avalanche Current	L = 0.1 mH	I <sub>AS</sub>	20		
Single Pulse Avalanche Energy		E <sub>AS</sub>	20	mJ	
	T <sub>C</sub> = 25 °C		5.9		
Maximum Pawar Dissipation	T <sub>C</sub> = 70 °C	1 5 [	3.8	w	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>b, c</sup>	VV	
	T <sub>A</sub> = 70 °C	1	2 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS								
Parameter		Symbol	Typical	Maximum	Unit			
Maximum Junction-to-Ambient <sup>b, †</sup>	t ≤ 10 s	R <sub>thJA</sub>	33	40	°C/W			
Maximum Junction-to-Foot (Drain)	Steady State	$R_{thJF}$	17	21	7 0/1/			

- a. Based on  $T_C$  = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 s.
- d. Maximum under steady state conditions is 80 °C/W.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Т.		172		mV/°C
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I <sub>D</sub> = 250 μA		- 10		mv/·C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = 250 \mu\text{A}$	$V_{DS} = V_{GS}$ , $I_D = 250 \mu\text{A}$ 1.5		3.0	V
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Cata Valtana Duain Comment		V <sub>DS</sub> = 150 V, V <sub>GS</sub> = 0 V			1	
Zero Gate Voltage Drain Current	IDSS	$V_{DS} = 120 \text{ V}, V_{GS} = 0 \text{ V}, T_{J} = 55 ^{\circ}\text{C}$			10	μΑ
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	$V_{DS} \ge 10 \text{ V}, V_{GS} = 10 \text{ V}$	30			Α
Dunin Course On Chata Basistanas		$V_{GS} = 10 \text{ V, } I_{D} = 5 \text{ A}$		0.074		Ω
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	$V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		0.077		
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	$V_{DS} = 15 \text{ V}, I_{D} = 5 \text{ A}$		23		S
Dynamic <sup>b</sup>			•			
Input Capacitance	C <sub>iss</sub>			1735		
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		160		pF
Reverse Transfer Capacitance	C <sub>rss</sub>			37		
Total Cata Channa	Q <sub>g</sub>	$V_{DS} = 75 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		28.5	43	
Total Gate Charge				23	35	200
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 75 \text{ V}, V_{GS} = 8 \text{ V}, I_{D} = 5 \text{ A}$		8		nC
Gate-Drain Charge	Q <sub>gd</sub>			6.5		
Gate Resistance	$R_{g}$	f = 1 MHz	3.0		1.3	Ω
Turn-on Delay Time	t <sub>d(on)</sub>			14	21	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 50 V, $R_L$ = 10 $\Omega$		12	18	=
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		22	33	
Fall Time	t <sub>f</sub>			6	10	200
Turn-On Delay Time	t <sub>d(on)</sub>			16	24	ns -
Rise Time	t <sub>r</sub>	$V_{DD}$ = 50 V, $R_L$ = 10 $\Omega$		12	18	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong 5$ A, $V_{GEN}$ = 8 V, $R_g$ = 1 $\Omega$		20	30	
Fall Time	t <sub>f</sub>			7	12	
<b>Drain-Source Body Diode Characteristi</b>	cs					
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			7.7	A
Pulse Diode Forward Current <sup>a</sup>	I <sub>SM</sub>				50	^
Body Diode Voltage	V <sub>SD</sub>	I <sub>S</sub> = 2.6 A		0.77	1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			63	95	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	I <sub>E</sub> = 5 A, dI/dt = 100 A/μs, T <sub>.1</sub> = 25 °C		110	165	nC
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 5 \text{ A}$ , $UI/UI = 100 \text{ A}/\mu\text{S}$ , $I_J = 25 \text{ C}$		49		nc
Reverse Recovery Rise Time	t <sub>b</sub>			14		ns

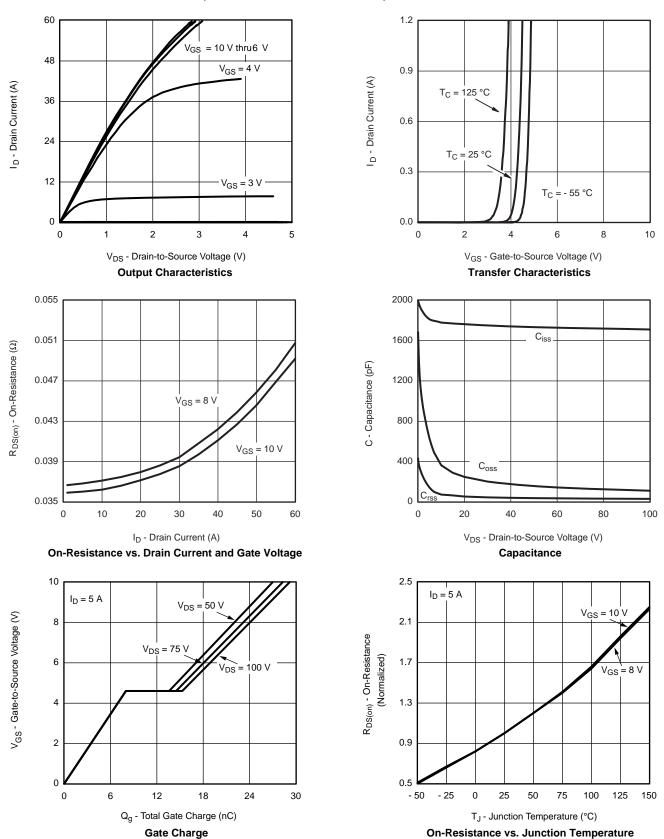
#### Notes:

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

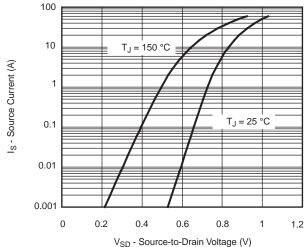
a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$ 

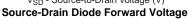
a. Guaranteed by design, not subject to production testing.

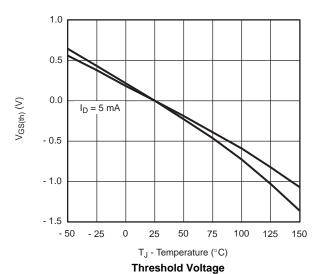




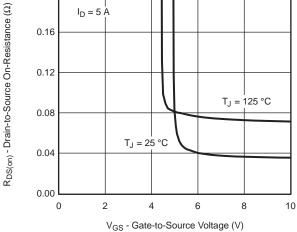




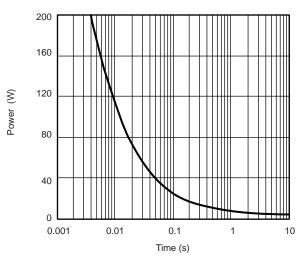




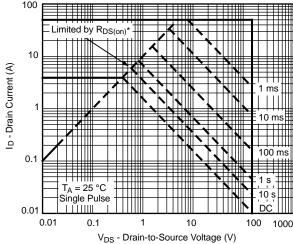
0.20  $I_D = 5 \text{ A}$ 0.16 0.12 0.08 0.04 0.00



On-Resistance vs. Gate-to-Source Voltage



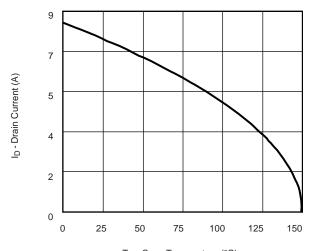
Single Pulse Power, Junction-to-Ambient



\*  $V_{GS}$  > minimum  $V_{GS}$  at which  $R_{DS(on)}$  is specified

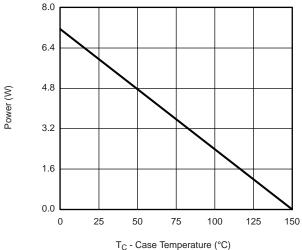
Safe Operating Area, Junction-to-Ambient

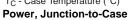


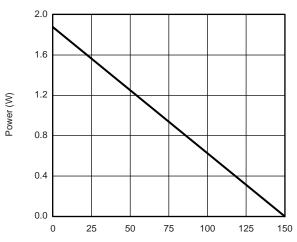


T<sub>C</sub> - Case Temperature (°C)





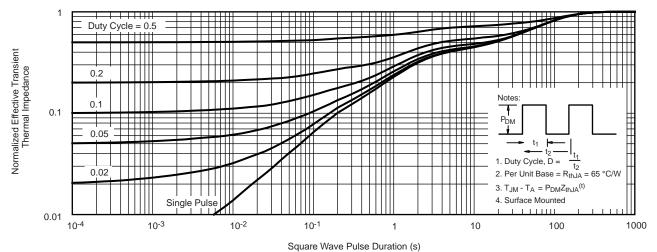




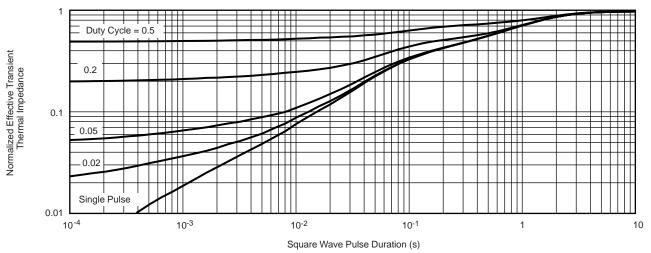
T<sub>A</sub> - Ambient Temperature (°C) **Power, Junction-to-Ambient** 

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





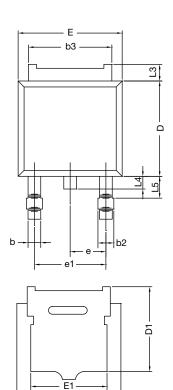
Normalized Thermal Transient Impedance, Junction-to-Ambient

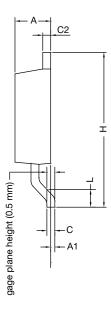


Normalized Thermal Transient Impedance, Junction-to-Foot



## **TO-252AA CASE OUTLINE**





	MILLIMETERS		INC	HES	
DIM.	MIN.	MAX.	MIN.	MAX.	
А	2.18	2.38	0.086	0.094	
A1	-	0.127	-	0.005	
b	0.64	0.88	0.025	0.035	
b2	0.76	1.14	0.030	0.045	
b3	4.95	5.46	0.195	0.215	
С	0.46	0.61	0.018	0.024	
C2	0.46	0.89	0.018	0.035	
D	5.97	6.22	0.235	0.245	
D1	5.21	-	0.205	-	
Е	6.35	6.73	0.250	0.265	
E1	4.32	-	0.170	-	
Н	9.40	10.41	0.370	0.410	
е	2.28	BSC	0.090 BSC		
e1	4.56 BSC		0.180 BSC		
L	1.40	1.78	0.055	0.070	
L3	0.89	1.27	0.035	0.050	
L4	-	1.02	-	0.040	
L5	1.14	1.52	0.045	0.060	
ECN: X12-0247-Rev. M. 24-Dec-12					

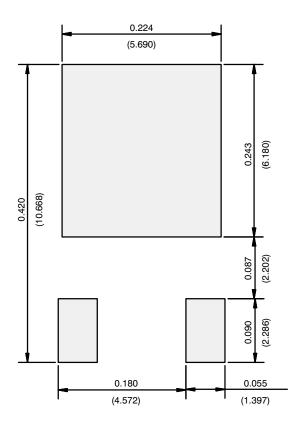
ECN: X12-0247-Rev. M, 24-Dec-12 DWG: 5347

#### Note

• Dimension L3 is for reference only.



### **RECOMMENDED MINIMUM PADS FOR DPAK (TO-252)**



Recommended Minimum Pads Dimensions in Inches/(mm)



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